

PRODUCT BULLETIN #20726

Generic Copy

Issue Date: 14-Jan-2015

TITLE: New datasheet revision of HAS2 Space Image Sensor.

PROPOSED FIRST SHIP DATE: Effective Immediately

AFFECTED CHANGE CATEGORY(S): New datasheet revision

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor sales office or < Gretel.willems@onsemi.com>

NOTIFICATION TYPE:

ON Semiconductor considers this change approved unless specific conditions of acceptance are provided in writing. To do so, contact < quality @onsemi.com>.

DESCRIPTION of CHANGEPURPOSE:

This is to announce the release of a new HAS2 datasheet revision, revision 14. The revision changes can be found in the Appendix below. Additionally, the datapack accompanying each NOIH2SM1000S or NOIH2SM1000T delivery is going to be structurally updated. Datapack changes can be found in the Appendix below.

List of Affected General Parts:

NOIH2SM1000A-HHC NOIH2SM1000S-HHC NOIH2SM1000T-HHC NOIH2SM1000A-HWC NOIH2SM1000S-HWC

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Appendix

HAS2 Datasheet Revision History

Revision	ECN	Origin of change	Submission date	Description of Change
14		TECH PUBS	January 2015	Page 1, first sentence is removed and "specification" is replaced by "datasheet". Page 1, Component Type Values section is replaced. Page 1, Pin Assignment figure and page references are corrected. Page 1, Limited Warranty section is removed. Page 2, Additional Information section is rephrased. Page 2, ITAR information section is rephrased. Table 2, document numbers are converted to ONSemi numbers ADO1 and ADO6 are removed, Issue and Date columns are removed. Deviation from Generic Specification section is rephrased. Page 3, Level 2 versus Level 1 differences section is rephrased and updated. Page 5, Parameter Drift Values 2nd paragraph is rephrased. Page 6, Amount of krad is corrected. Table 6, test location column is removed. Table 7, number of devices field in "Geometrical measurements" is changed, test location column is removed, document numbers are converted to ONSemi numbers, line items "Temperature cycling around dew point" and "RGA" are added. Page 7, Conditions for leak tests are added. Table 8, test location column is removed. Table 9, unbiased stabilization bake (48h) is done prior to Electrical measurements, test location column is removed, and document numbers are converted to ONSemi numbers. Figure 2 LAT flow is adjusted. Table 14, Die position X/Y tilt" is changed, tolerance of "Distance from top of the die surface to top of the glass lid" is added and die rotation accuracy is changed. Figure 3 is adjusted. Table 19, Average dark signal and Average DSNU @-40 deg limits are removed. Table 20, Average dark signal and Average DSNU @-40 deg limits are removed. Table 21, drift limits table is updated. All temperature references are changed to 22°C. Table 24, is rephrased. Table 17, 18, 19, 20, 25 and 26, Output Amplifier Offset limits Operational current limits and standby current limits are updated.

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HAS2 Datapack Changes

Datapack changes

Description of Change

Appendix 1 of datapacks (Datasheet): Datasheet will not be attached in datapacks. Datasheet is available in MyON Appendix 2 of datapacks (Electro-optical test methods): NPD-0064422: IS_Characterization_Standard_v1.01.pdf replaces the Electro-optical test methods for CMOS image sensors V1_0.pdf. The new file has also characterization information while the previous had only test methods described.

Appendix 6 of datapacks (electrical measurements data): STAR1000's 001-66578 and HAS2's 001-64028 will be removed. Addition of measurement units and conversion to datasheet units. Revision controlled. Only Datasheet and calibration parameters included.

Test software revision will not be mentioned. Any major change on our test plan will be communicated to the customers via PCN Results per illumination level will no longer be reported. Only result as per the parameter in the datasheet. (For example, the column test at dark, gray and saturation level will not be provided. The results are included in 801 tests.) Also pre-screening measurements will be delivered.

Appendix 7 of datapacks and TRC report (spectral response of reference lot): The appendix with the spectral response of the reference lot is removed. All WLAT spectral response excel files have been updated with the reference lot's data

Appendix 8 of datapacks (ESCC docs): ESCC docs removed. Replaced by 'NPD-0067186 HAS2/STAR1000 Deviations to the ESCC-9020 (added to the datapack)"

Appendix 9 of datapacks (screening reports): A list of the screened devices and their electrical results will be added. ATE bin swaps of the screened devices will be marked.

Appendix 10 of datapacks (Assembly LAT data): RGA results: moisture stressed devices results will be removed from the LAT report

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